

SOLID STATE DEVICES, INC.

14005 Stage Road * Santa Fe Springs, Ca 90670 Phone: (562) 404-4474 * Fax: (562) 404-1773

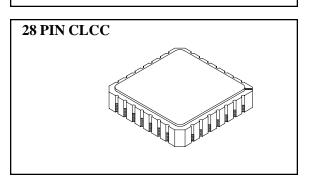
DESIGNER'S DATA SHEET

FEATURES:

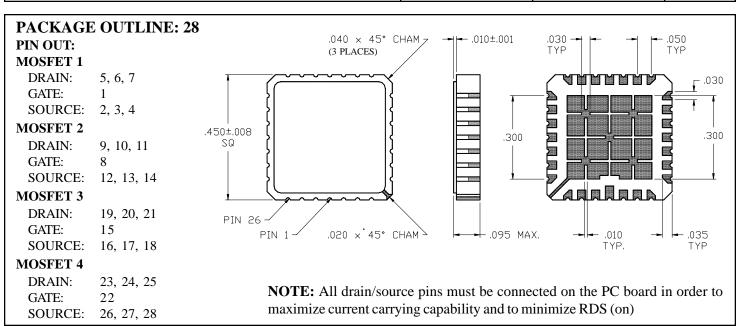
- Rugged construction with poly silicon gate
- Low RDS (on) and high transconductance
- Excellent high temperature stability
- Very fast switching speed
- Fast recovery and superior dv/dt performance
- · Increased reverse energy capability
- Low input and transfer capacitance for easy paralleling
- Hermetically sealed surface mount package
- TX, TXV and Space Level screening available
- Replaces 4x IRF120 Types in One Package

SFF120-28Q

9.2 AMPS 100 VOLTS 0.35Ω QUAD N-CHANNEL POWER MOSFET



MAXIMUM RATINGS			
CHARACTERISTIC	SYMBOL	VALUE	UNIT
Drain to Source Voltage	$ m V_{DS}$	100	Volts
Gate to Source Voltage	$ m V_{GS}$	±20	Volts
Continuous Drain Current	I _D 9.2		Amps
Operating and Storage Temperature	Top & Tstg	-55 to +150	°C
Thermal Resistance, Junction to Case (All Four)	$R_{ heta JC}$	10	°C/W
Total Device Dissipation @ $TC = 25^{\circ}C$ @ $TC = 70^{\circ}C$	P _D	12.5 9.5	Watts



SFF120-28Q

PRELIMINARY



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ELECTRICAL CHARACTERISTICS @ $T_J = 25$ °C (Unless Otherwise Specified)									
RATING		SYMBOL	MIN	TYP	MAX	UNIT			
Drain to Source Breakdown Voltage (VGS =0 V, ID =250µA)		BV _{DSS}	100	-	-	V			
Drain to Source ON State Resistance (VGS = 10 V, 60% of Rated ID)		R _{DS(on)}	-	-	0.35	Ω			
ON State Drain Current (VDS > ID(on) x RDS(on) Max, VGS = 10 V)		I _{D(on)}	9.2	-	-	A			
Gate Threshold Voltage (VDS = VGS, ID = 250 µA)		V _{GS(th)}	2.0	-	4.0	V			
Forward Transconductance (VDS > ID(on) x RDS (on) Max, IDS =60% rated ID)		gf _s	2.7	4.1	-	S (0)			
$\label{eq:Zero Gate Voltage Drain Current} \begin{aligned} \textbf{(V}_{DS} &= \text{max rated Voltage, V}_{GS} = 0 \textbf{V}) \\ \textbf{(V}_{DS} &= 80\% \text{ rated V}_{DS}, \textbf{V}_{GS} = 0 \textbf{V}, \textbf{T}_{A} = 125^{\circ} \textbf{C}) \end{aligned}$		$I_{ m DSS}$	-	- -	25 250	μΑ			
Gate to Source Leakage Forward Gate to Source Leakage Reverse	At rated VGS	I_{GSS}		-	+100 -100	nA			
Total Gate Charge Gate to Source Charge Gate to Drain Charge	VGS = 10 V 80% rated VDS 60% rated ID	Qg Qgs Qgd		10.7 2.9 5.1	16 4.4 7.7	nC			
Turn on Delay Time Rise Time Turn off DELAY Time Fall Time	VDD=50% rated VDS 50% rated ID RG = 18 Ω	$\begin{array}{c} t_{d~(on)} \\ tr \\ t_{d~(off)} \\ tf \end{array}$	- - -	13 30 19 20	20 45 29 30	nsec			
Diode Forvard Voltage (I _S = rated I _D , V _{GS} = 0V, T _J = 25°C)		V _{SD}	-	-	2.5	V			
Diode Reverse Recovery Time Reverse Recovery Charge	TJ =25°C IF = rated ID di/dt = 100A/μsec	t _{rr} Q _{RR}	55 0.25	140 0.65	260 1.3	nsec μC			
Input Capacitance Output Capacitance Reverse Transfer Capacitance	VGS =0 Volts VDS =25 Volts f =1 MHz	Ciss Coss Crss	-	350 130 36	-	pF			

For thermal derating curves and other characteristic curves please contact SSDI Marketing Department.

NOTES: